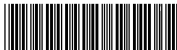


**Search Notes****Application/Control No.**

10/553,043

**Examiner**

/Yonel Beaulieu/

**Applicant(s)/Patent under  
Reexamination**

NIHEI ET AL.

**Art Unit**

3661

**SEARCHED**

Class	Subclass	Date	Examiner
701	1-2	4/1/2009	YB
	29		
	36		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Searched		4/1/2009	YB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Int.+Fwd/Bwd	4/1/2009	YB